

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

Expected First Shipment Date for Changed Product : Feb. 23, 2014

Expected First Date Code of Changed Product :1405

Description of Change (From) :

Manufacturing source at FSC China Subcontractor located in Jiangyin city, JiangSu province, China.

Description of Change (To) :

Manufacturing source at FSC China Subcontractor located in Chuzhou city, Anhui province, China.

BOM Comparison Table

Process/Material	Manufacturing source in JiangYin	Manufacturing source in Chuzhou
Lead Frame	Alloy42	Alloy42
Die attach	Eutectic	Eutectic
Wire bonding	Au	Au
Molding	ELL-2K1 / ELER-8-100HFE	ELER-8-100HFE

Reason for Change:

Fairchild's China Subcontractor moved their manufacturing facility from Jiangyin City to Chuzhou City. The Jiangyin City manufacturing facility has closed the assemble line. Package outline drawings of the affected products remain unchanged. The affected product will be fully compliant to all the published data sheet specifications and this change will have no impact on their electrical performance. The Quality and reliability will remain at the highest standards already demonstrated with Fairchild's existing product.

Affected Product(s): Please refer to the list of affected products in the addendum attached in the PCN email you received. This list is based on an analysis of your company's procurement history.

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	2N7002	SOT23	DMOS	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias Test	150C, 100% of rated VGS	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	FDV301N	SOT23	LV Mosfet	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias Test	150C, 100% of rated VGS	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130064	FDV304P	SOT23	LV Mosfet	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias Test	150C, 100% of rated VGS	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q1205167B	2N7002W	SOT323	DMOS	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Gate Bias Test	150C, 100% of rated VGS	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q1205167B	BAT54SWT1G	SOT323	Schottky	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q1205167B	FJX2222ATF	SOT323	SS-TR	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 80% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750-1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77